

FCC ID: 2AV3G-TX12

Page 1 of 62

FCC SAR Test Report

: Shenzhen RadioMaster Technology Co., Ltd **Client Name**

5th Flr, Building 9, Mabian Industrial Park, No. 72, Xingdong Address community, Bao'an District, Shenzhen, China

Product Name TX12

Date Dec. 03, 2020

Compliance Laboration Shenzhen Anbotek Compliance Laboratory Limited

Approved

 \mathbf{N}

Shenzhen Anbotek Compliance Laboratory Limited

Address: 1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 755-26066440 Fax: (86) 755-26014772 Email: service@anbotek.com



FCC ID: 2AV3G-TX12 Pa

Page 2 of 62

Contents

1. Statement of Compliance				All stek C
1. Statement of Compliance	an Autorites		hupotok	
2. General Information 2.1 Client Information	stek nobo	pak pubotek		
2. 2 Description of Equipment Under Test (EUT)		Lotek M	pover P	
2. 3 Device Category and SAR Limits2. 4 Applied Standard	Anboyer		nbolek	8
2. 4 Applied Standard 2. 5 Environment of Test Site	Anbotok	Nucleo -	hi	
2. 5 Environment of Test Site 2. 6 Test Configuration	K shotek	Anbore	partek	8
2. 6 Test Configuration		ek anbotek	No.	
3. Specific Absorption Rate (SAR)		tel table		
3.1 Introduction	nipotek Ali		oten An	
3. 2 SAR Definition	hoten	Aupote	stell	
4. SAR Measurement System				
4.1 E-Field Probe		-botek	Antoole	11
4. 2 Data Acquisition Electronics (DAE)	- Autoons		Anosten	11
4. 3 Robot	net anot	2 ⁵	X	
4. 4 Measurement Server				
4.5 Phantom				
4.6 Device Holder				
4.7 Data Storage and Evaluation	- Antorek	pripo.		16
 5. Test Equipment List 6. Tissue Simulating Liquids 		palaone	Anne	
6. Tissue Simulating Liquids		Kupotek	Aupo	19
7 System Verification Procedures				21
8. EUT Testing Position	dna ^{Marco}	ore pre-	تنبي	
9. Measurement Procedures	Pun.		nbo.	24
9.1 Spatial Peak SAR Evaluation	Aupo.		pobote	
9.2 Power Reference Measurement	pabote	An		25
9.3 Area Scan Procedures	ak	Anbu		
9.4 Zoom Scan Procedures		stek Anbois		
9.5 Volume Scan Procedures	90. Pr.	odine Heren	Her And	27
9.6 Power Drift Monitoring	pobote. N		hotek	27
 9. 3 Area Scan Procedures 9. 4 Zoom Scan Procedures 9. 5 Volume Scan Procedures 9. 6 Power Drift Monitoring 10. Conducted Power 	nbotek	Anbo. A		
 SAR Test Results Summary Simultaneous Transmission Analysis 	botek	Anbore	Am	
12. Simultaneous Transmission Analysis	Allin	anboten	Ande	
Similianeous LX SAR Considerations				
Evaluation of Simultaneous SAR	jotek Anbo		ek pubo	Anu
13. Measurement Uncertainty	hotek M	ibote. Anu		
Appendix A. EUT Photos and Test Setup P	hotos	anboten Ar	19 ²	
Appendix B. Plots of SAR System Check	And	botek	Anbor	
an 11	Anboi	Austek	Anboten	Anusak
Shenzhen Anbotek Compliance Laboratory Limited	d boten	Ano	Lotek	Anboi

Address: 1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 755–26066440 Fax: (86) 755–26014772 Email: service@anbotek.com



Report No.: 18220WC00163202	FCC ID: 2AV3G-TX12		Page 3 of 62	
Appendix C. Plots of SAR Test Data	unpolen pro-	lato,	Support	.35
Appendix D. DASY System Calibration Ce	rtificate		ret poboten	37

Shenzhen Anbotek Compliance Laboratory Limited

Address: 1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 755–26066440 Fax: (86) 755–26014772 Email: service@anbotek.com



FCC ID: 2AV3G-TX12

Page 4 of 62

TEST REPORT

Applicant	Shenzhen RadioMaster Technology Co., Ltd
Manufacturer	: Shenzhen RadioMaster Technology Co., Ltd
Product Name	TX12 Andreak Andreak Andreak Andreak Andreak Andreak Andreak Andreak
Model No.	TX12, TX12 HALL, TX12 Carbon, TX12 Gold, TX12 Silver, TX12 Max, TX12 SE, TX12 Pro, TX12 LRS, TX12 Lite, TX12 Metal, TX12 MG
Trade Mark	: Radiomaster
Rating(s)	: Input: DC 6.6-8.4V,160mA

Test Standard(s) : IEEE 1528:2013; IEC 62209-2:2010; FCC 47 CFR Part 2 (2.1093:2013);

ANSI/IEEE C95.1:2005;Reference FCC KDBs;

The device described above is tested by Shenzhen Anbotek Compliance Laboratory Limited to determine the maximum emission levels emanating from the device and the severe levels of the device can endure and its performance criterion. The measurement results are contained in this test report and Shenzhen Anbotek Compliance Laboratory Limited is assumed full of responsibility for the accuracy and completeness of these measurements. Also, this report shows that the EUT (Equipment Under Test) is technically compliant with the IEEE 1528:2013, IEC 62209-2:2010, FCC 47 CFR Part 2 (2.1093:2013), ANSI/IEEE C95.1:2005, and Reference FCC KDBs requirements.

This report applies to above tested sample only and shall not be reproduced in part without written approval of Shenzhen Anbotek Compliance Laboratory Limited.

Date of Receipt Date of Test

Prepared By

Nov.05, 2020 Nov.05, 2020~Nov.26, 2020

King Kom

(Engineer / Kingkong Jin)

Reviewer

Bibs Than

(Supervisor / Bibo Zhang)

C

Approved & Authorized Signer

(Manager / Tom Chen)

Shenzhen Anbotek Compliance Laboratory Limited

Address: 1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 755-26066440 Fax: (86) 755-26014772 Email: service@anbotek.com



FCC ID: 2AV3G-TX12

Page 5 of 62



Version No.	Date		Description	
01	Nov. 26, 2020	and anbotek	Original	Anbotek An
Anbo Anborek A	botek Anbou	Anbotek Anbote	kek anbotek	Anbotek
wotek Anbotek	Anboten Anto	Anbotek Anb	John Anbotek	Anboten
nbotek Anbotek	Anboin Anb	stek Anboren I	Anborek Anbo	tek Anbour
Anbotek Anbote	ek obotek A	hbotek Anbo	Anbotek An	boto. Ann
Anboten Anbo	hotek Anbotek	Anboto Ann	K Anborek	Anbonotek
lek Anboin An	botek Anboten	And stek	otek Anbois	Ar. hotek

Shenzhen Anbotek Compliance Laboratory Limited





1. Statement of Compliance

The maximum results of Specific Absorption Rate (SAR) found during testing are as follows.

<Highest SAR Summary>

Eroguopov Bond	Highest Reported 1g-SAR(W/Kg)	SAR Test Limit (W/Kg)	
Frequency Band	Body-worn(0mm)		
2.4G TX	0.407	1.6 mbore	
Test Result	PASS	Anbo	

This device is in compliance with Specific Absorption Rate (SAR) for general population/uncontrolled exposure limits (1.6 W/kg) specified in KDB 447498 D01 v06, 2015 and ANSI/IEEE C95.1-2005, and had been tested in accordance with the measurement methods and procedures specified in IEEE 1528-2013

Shenzhen Anbotek Compliance Laboratory Limited

Address: 1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 755–26066440 Fax: (86) 755–26014772 Email: service@anbotek.com



2. General Information

2.1 Client Information

Applicant	:	Shenzhen RadioMaster Technology Co., Ltd
Address	:	5th Flr, Building 9, Mabian Industrial Park, No. 72, Xingdong community, Bao'an District, Shenzhen, China
Manufacturer	:	Shenzhen RadioMaster Technology Co., Ltd
Address	:	5th Flr, Building 9, Mabian Industrial Park, No. 72, Xingdong community, Bao'an District, Shenzhen, China
Factory	:	Shenzhen RadioMaster Technology Co., Ltd
Address	:	5th Flr, Building 9, Mabian Industrial Park, No. 72, Xingdong community, Bao'an District, Shenzhen, China

2. 2 Description of Equipment Under Test (EUT)

Product Name	:	TX12
Model No.	:	TX12, TX12 HALL, TX12 Carbon, TX12 Gold, TX12 Silver, TX12 Max, TX12 SE, TX12 Pro, TX12 LRS, TX12 Lite, TX12 Metal, TX12 MG
Trade Mark	:	Radiomaster
Test Power Supply	:	DC 7.4V battery inside
Tx Frequency	:	2416-2466MHz
Type of Modulation	:	GFSK
Antenna Type	:	Cylindrical antenna
Antenna Gain(Peak)	:	2 dBi
Hardware version	:	V1.04
Software version	:	V1.0 Model Model Model
Product Serial Number	:	2AF1A0F1EA90
Category of device	:	Portable device

or the User's Manual.

Shenzhen Anbotek Compliance Laboratory Limited

FCC ID: 2AV3G-TX12

Page 8 of 62

2. 3 Device Category and SAR Limits

This device belongs to portable device category because its radiating structure is allowed to be used within 20 centimeters of the body of the user. Limit for General Population/Uncontrolled exposure should be applied for this device, it is 1.6 W/kg as averaged over any 1 gram of tissue.

2. 4 Applied Standard

The Specific Absorption Rate (SAR) testing specification, method, and procedure for this device is in accordance with the following standards:

- FCC 47 CFR Part 2 (2.1093:2013)
- ANSI/IEEE C95.1:2005
- IEEE Std 1528:2013
- KDB 865664 D01 SAR Measurement 100 MHz to 6 GHz v01r04
- KDB 865664 D02 RF Exposure Reporting v01r02
- KDB 447498 D01 General RF Exposure Guidance v06
- KDB248227 D01 802 11 Wi-Fi SAR v02r02
- KDB941225 D01 3G SAR Procedures v03r01
- KDB 941225 D05 SAR for LTE Devicesv02r05
- KDB 941225 D06 Hotspot SARv02r01
- KDB648474 D04 Handset SAR v01r03

2.5 Environment of Test Site

Items	Required	Actual
Temperature (°C)	18-25	22~23
Humidity (%RH)	30-70	55~65

2.6 Test Configuration

For 2.4G SAR testing, engineering testing software installed on the EUT can provide continuous transmitting RF signal.

Shenzhen Anbotek Compliance Laboratory Limited



3. Specific Absorption Rate (SAR)

3.1 Introduction

Anbotek

Product Safety

SAR is related to the rate at which energy is absorbed per unit mass in an object exposed to a radio field. The SAR distribution in a biological body is complicated and is usually carried out by experimental techniques or numerical modeling. The standard recommends limits for two tiers of groups, occupational/controlled and general population/uncontrolled, based on a person's awareness and ability to exercise control over his or her exposure. In general, occupational/controlled exposure limits higher the limits are than for general population/uncontrolled.

3. 2 SAR Definition

The SAR definition is the time derivative (rate) of the incremental energy (dW) absorbed by (dissipated in) an incremental mass (dm) contained in a volume element (dv) of a given density (ρ). The equation description is as below:

$$SAR = \frac{d}{dt} \left(\frac{dW}{dm} \right) = \frac{d}{dt} \left(\frac{dW}{\rho dv} \right)$$

SAR is expressed in units of Watts per kilogram (W/kg)

SAR measurement can be either related to the temperature elevation in tissue by

$$SAR = C\left(\frac{\delta T}{\delta t}\right)$$

Where: C is the specific head capacity, δT is the temperature rise and δt is the exposure duration, or related to the electrical field in the tissue by

$$SAR = \frac{\sigma |E|^2}{\rho}$$

Where: σ is the conductivity of the tissue, ρ is the mass density of the tissue and E is the RMS electrical field strength.

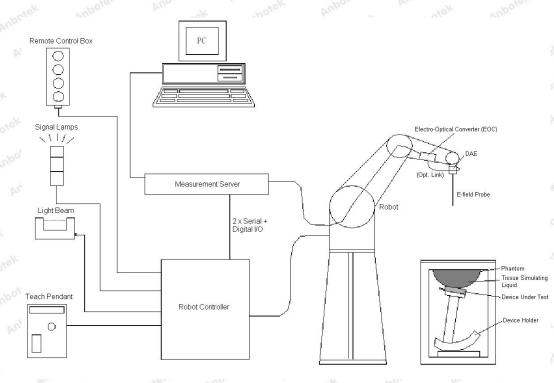
However for evaluating SAR of low power transmitter, electrical field measurement is typically applied.

Shenzhen Anbotek Compliance Laboratory Limited



FCC ID: 2AV3G-TX12 Page 10 of 62

4. SAR Measurement System



DASY System Configurations

The DASYsystem for performance compliance tests is illustrated above graphically. This system consists of the following items:

- > A standard high precision 6-axis robot with controller, a teach pendant and software
- > A data acquisition electronic (DAE) attached to the robot arm extension
- > A dosimetric probe equipped with an optical surface detector system
- The electro-optical converter (EOC) performs the conversion between optical and electrical signals
- A measurement server performs the time critical tasks such as signal filtering, control of the robot operation and fast movement interrupts.
- > A probe alignment unit which improves the accuracy of the probe positioning
- > A computer operating Windows XP
- DASY software
- Remove control with teach pendant and additional circuitry for robot safety such as warming lamps, etc.
- The SAM twin phantom
- A device holder
- Tissue simulating liquid
- > Dipole for evaluating the proper functioning of the system

Shenzhen Anbotek Compliance Laboratory Limited





Report No.: 18220WC00163202 FCC ID: 2AV3G-TX12

Page 11 of 62

components are described in details in the following sub-sections.

4.1 E-Field Probe

The SAR measurement is conducted with the dosimetric probe (manufactured by SPEAG). The probe is specially designed and calibrated for use in liquid with high permittivity. The dosimetric probe has special calibration in liquid at different frequency. This probe has a built in optical surface detection system to prevent from collision with phantom.

E-Field Probe Specification <EX3DV4 Probe>

	April 194	60	- 250
Construction	Symmetrical design with triangular core		unbr
	Built-in shielding against static charges		
	PEEK enclosure material (resistant to	tek	
	organic solvents, e.g., DGBE)	2.2	
Frequency	10 MHz to 6 GHz; Linearity: ± 0.2 dB		
Directivity	± 0.3 dB in HSL (rotation around probe	Martin Contraction of the State	
	axis)	Statement Statements	
	± 0.5 dB in tissue material (rotation	the second s	
	normal to probe axis)	d+	
Dynamic Range	10 μ W/g to 100 mW/g; Linearity: ± 0.2	1	
	dB (noise: typically < 1 μW/g)	Photo of EX3DV4	
Dimensions	Overall length: 330 mm (Tip: 20 mm)		
c	Tip diameter: 2.5 mm (Body: 12 mm)		
	Typical distance from probe tip to		
	dipole centers: 1 mm	ak abotek Anboten	PU

E-Field Probe Calibration

Each probe needs to be calibrated according to a dosimetric assessment procedure with accuracy better than \pm 10%. The spherical isotropy shall be evaluated and within \pm 0.25dB. The sensitivity parameters (NormX, NormY, and NormZ), the diode compression parameter (DCP) and the conversion factor (ConvF) of the probe are tested. The calibration data can be referred to appendix C of this report.

4. 2 Data Acquisition Electronics (DAE)

The data acquisition electronics (DAE) consists of a highly sensitive electrometer-grade preamplifier with auto-zeroing, a channel and gain-switching multiplexer, a fast 16 bit AD-converter and a command decoder and control logic unit. Transmission to the measurement server is accomplished through an optical downlink for data and status information as well as an optical uplink for commands and the clock.

Shenzhen Anbotek Compliance Laboratory Limited

Address: 1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 755–26066440 Fax: (86) 755–26014772 Email: service@anbotek.com



Report No.: 18220WC00163202 FCC ID: 2AV3G-TX12 Page 12 of 62

The input impedance of the DAE is 200MOhm; the inputs are symmetrical and floating. Common mode rejection is above 80dB.



Photo of DAE

4.3 Robot

The SPEAG DASY system uses the high precision robots (DASY5: TX60XL) type from Stäubli SA (France). For the 6-axis controllersystem, the robot controller version (DASY5: CS8c) from Stäubli is used. The Stäubli robot series have many features that are important for our application:

- High precision (repeatability ±0.035 mm)
- High reliability (industrial design)
- Jerk-free straight movements
- > Low ELF interference (the closed metallic construction shields against motor control fields)



Photo of DASY5

4.4 Measurement Server

The measurement server is based on a PC/104 CPU board with CPU (DASY5: 400 MHz, Intel

Shenzhen Anbotek Compliance Laboratory Limited

Address: 1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 755–26066440 Fax: (86) 755–26014772 Email: service@anbotek.com



FCC ID: 2AV3G-TX12 Pa

Page 13 of 62

Celeron), chipdisk (DASY5: 128 MB), RAM (DASY5: 128 MB). The necessary circuits for communication with the DAE electronic box, as well as the 16 bit AD converter system for optical detection and digital I/O interface are contained on the DASY I/O board, which is directly connected to the PC/104 bus of the CPU board.

The measurement server performs all the real-time data evaluation for field measurements and surface detection, controls robot movements and handles safety operations.



Photo of Server for DASY5

4.5 Phantom

<SAM Twin Phantom>

Shell Thickness	2 ± 0.2 mm;
	Center ear point: 6 ± 0.2 mm
Filling Volume	Approx. 25 liters
Dimensions	Length: 1000 mm; Width: 500 mm;
	Height: adjustable feet
Measurement	Left Hand, Right Hand, Flat
Areas	Phantom Phantom
	Anbor Ar bolek Anbole
	Anborn Ann otek Anboren tek sobor

Photo of SAM Phantom

The bottom plate contains three pair of bolts for locking the device holder. The device holder positions are adjusted to the standard measurement positions in the three sections. A white cover is provided to tap the phantom during off-periods to prevent water evaporation and changes in the liquid parameters. On the phantom top, three reference markers are provided to identify the phantom position with respect to the robot.

Shenzhen Anbotek Compliance Laboratory Limited



FCC ID: 2AV3G-TX12

<ELI4 Phantom>

Shell Thickness	2 ± 0.2 mm (sagging: <1%)
Filling Volume	Approx. 30 liters
Dimensions	Major ellipse axis: 600 mm
	Minor axis:400 mm
	Anbotek Anbotek Anbotek Anbotek Anbotek Anbotek A
	Anbotek Anbotek Anbotek
	Photo of ELI4 Phantom

The ELI4 phantom is intended for compliance testing of handheld and body-mounted wireless devices in the frequency range of 30 MHz to 6 GHz. ELI4 is fully compatible with standard and all known tissue simulating liquids.

Shenzhen Anbotek Compliance Laboratory Limited



FCC ID: 2AV3G-TX12

Page 15 of 62

4.6 Device Holder

Anbotek

Product Safety

The SAR in the phantom is approximately inversely proportional to the square of the distance between the source and the liquid surface. For a source at 5 mm distance, a positioning uncertainty of ± 0.5 mm would produce a SAR uncertainty of $\pm 20\%$. Accurate device positioning is therefore crucial for accurate and repeatable measurements. The positions in which the devices must be measured are defined by the standards.

The DASY device holder is designed to cope with different positions given in the standard. It has two scales for the device rotation (with respect to the body axis) and the device inclination (with respect to the line between the ear reference points). The rotation center for both scales is the ear reference point (ERP).Thus the device needs no repositioning when changing the angles.

The DASY device holder is constructed of low-loss POM material having the following dielectric parameters: relative permittivity ε = 3 and loss tangent δ = 0.02. The amount of dielectric material has been reduced in the closest vicinity of the device, since measurements have suggested that the influence of the clamp on the test results could thus be lowered.



Device Holder

Shenzhen Anbotek Compliance Laboratory Limited

Address: 1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 755–26066440 Fax: (86) 755–26014772 Email: service@anbotek.com

FCC ID: 2AV3G-TX12

Page 16 of 62

4. 7 Data Storage and Evaluation

Data Storage

The DASY software stores the assessed data from the data acquisition electronics as raw data (in microvolt readings from the probe sensors), together with all the necessary software parameters for the data evaluation (probe calibration data, liquid parameters and device frequency and modulation data) in measurement files. The post-processing software evaluates the desired unit and format for output each time the data is visualized or exported. This allows verification of the complete software setup even after the measurement and allows correction of erroneous parameter settings. For example, if a measurement has been performed with an incorrect crest factor parameter in the device setup, the parameter can be corrected afterwards and the data can be reevaluated.

The measured data can be visualized or exported in different units or formats, depending on the selected probe type (e.g., [V/m], [A/m], [mW/g]). Some of these units are not available in certain situations or give meaningless results, e.g., a SAR-output in a non-lose media, will always be zero. Raw data can also be exported to perform the evaluation with other software packages.

Data Evaluation

The DASY post-processing software (SEMCAD) automatically executes the following procedures to calculate the field units from the microvolt readings at the probe connector. The parameters used in the evaluation are stored in the configuration modules of the software:

Probe parameters:	- Sensitivity	Norn	n _i , a _{i0} , a _{i1} , a _{i2}
	- Conversion factor	ConvFi	
	- Diode compression poir	nt dcp _i	
Device parameters:	- Frequency	P ^{nu} f	
	- Crest factor	cf	
Media parameters:	- Conductivity	otek o M	
	- Density	P. ek	

These parameters must be set correctly in the software. They can be found in the component documents or they can be imported into the software from the configuration files issued for the DASY components. In the direct measuring mode of the multi-meter option, the parameters of the actual system setup are used. In the scan visualization and export modes, the parameters stored in the corresponding document files are used.

The first step of the evaluation is a linearization of the filtered input signal to account for the compression characteristics of the detector diode. The compensation depends on the input signal, the diode type and the DC-transmission factor from the diode to the evaluation electronics. If the exciting field is pulsed, the crest factor of the signal must be known to correctly compensate for peak power.

Shenzhen Anbotek Compliance Laboratory Limited

Address: 1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 755–26066440 Fax: (86) 755–26014772 Email: service@anbotek.com

Anbotek

Product Safety

The formula for each channel can be given as:

$$V_i = U_i + U_i^2 \cdot \frac{cf}{dcp_i}$$

FCC ID: 2AV3G-TX1

Page 17 of

with V_i = compensated signal of channel i, (i = x, y, z)

 U_i = input signal of channel i, (i = x, y, z)

cf = crest factor of exciting field (DASY parameter)

dcp_i = diode compression point (DASY parameter)

From the compensated input signals, the primary field data for each channel can be evaluated:

E-field Probes:
$$E_i = \sqrt{\frac{V_i}{Norm_i \cdot ConvF}}$$

 $\text{H-field Probes:} \ \ H_i = \sqrt{V_i} \cdot \frac{a_{i0} + a_{i1}f + a_{i2}f^2}{r}$

with V_i = compensated signal of channel i, (i = x, y, z) Norm_i= sensor sensitivity of channel i, (i = x, y, z), μV/(V/m)² for E-field Probes ConvF= sensitivity enhancement in solution a_{ij}= sensor sensitivity factors for H-field probes f = carrier frequency [GHz]

E_i= electric field strength of channel i in V/m

H_i= magnetic field strength of channel i in A/m

The RSS value of the field components gives the total field strength (Hermitian magnitude):

$$E_{tot} = \sqrt{E_x^2 + E_y^2 + E_z^2}$$

The primary field data are used to calculate the derived field units.

$$SAR = E_{tot}^2 \cdot \frac{\sigma}{\rho \cdot 1000}$$

with SAR = local specific absorption rate in mW/g

E_{tot}= total field strength in V/m

 σ = conductivity in [mho/m] or [Siemens/m]

 ρ = equivalent tissue density in g/cm³

Note that the density is set to 1, to account for actual head tissue density rather than the density of the tissue simulating liquid.

Shenzhen Anbotek Compliance Laboratory Limited



Anbotek Product Safety

Report No.: 18220WC00163202

FCC ID: 2AV3G-TX12

Page 18 of 62

5. Test Equipment List

Manufacturer	Nome of Equipment		Serial Number	Calib	ration
Wanutacturer	Name of Equipment	Type/Model	Serial Number	Last Cal.	Due Date
SPEAG	2450MHz System Validation Kit	D2450V2	910	Jun 15,2018	Jun 14,2021
Rohde & Schwarz	UNIVERSAL RADIO COMMUNICATION TESTER	CMU 200	117888	Oct.26, 2020	Oct.25, 2021
Rohde & Schwarz	UNIVERSAL RADIO COMMUNICATION TESTER	CMU 500	104209	Oct.26, 2020	Oct.25, 2021
SPEAG	Data Acquisition Electronics	DAE4	387	Sept.06,2020	Sept.05,2021
SPEAG	Dosimetric E-Field Probe	EX3DV4	7396	May 06,2020	May 05,2021
Agilent	ENA Series Network Analyzer	E5071C	MY46317418	Oct.26, 2020	Oct.25, 2021
SPEAG	DAK	DAK-3.5	1226	NCR	NCR
SPEAG	SAM Twin Phantom	QD000P40CD	1802	NCR	NCR
SPEAG	ELI Phantom	QDOVA004AA	2058	NCR	NCR
AR	Amplifier	ZHL-42W	QA1118004	NCR	NCR
Agilent	Power Meter	N1914A	MY50001102	Oct.26, 2020	Oct.25, 2021
Agilent	Power Sensor	N8481H	MY51240001	Oct.26, 2020	Oct.25, 2021
R&S	Spectrum Analyzer	N9020A	MY51170037	Oct.26, 2020	Oct.25, 2021
Agilent	Signal Generation	N5182A	MY48180656	Oct.26, 2020	Oct.25, 2021
Worken	Directional Coupler	0110A05601O- 10	COM5BNW1A2	Oct.26, 2020	Oct.25, 2021

Note:

- 1. The calibration certificate of DASY can be referred to appendix C of this report.
- 2. The dipole calibration interval can be extended to 3 years with justification. The dipoles are also not physically damaged, or repaired during the interval.
- 3. The Insertion Loss calibration of Dual Directional Coupler and Attenuator were characterized via the network analyzer and compensated during system check.
- The dielectric probe kit was calibrated via the network analyzer, with the specified procedure (calibrated in pure water) and calibration kit (standard) short circuit, before the dielectric measurement. The specific procedure and calibration kit are provided by Agilent.
- In system check we need to monitor the level on the power meter, and adjust the power amplifier level to have precise power level to the dipole; the measured SAR will be normalized to 1W input power according to the ratio of 1W to the input power to the dipole.
 - For system check, the calibration of the power amplifier is deemed not critically required for correct measurement; the power meter is critical and we do have calibration for it

Shenzhen Anbotek Compliance Laboratory Limited

FCC ID: 2AV3G-TX12

Page 19 of 62

6. Tissue Simulating Liquids

For the measurement of the field distribution inside the SAM phantom with DASY, the phantom must be filled with around 25 liters of homogeneous body tissue simulating liquid. For head SAR testing, the liquid height from the ear reference point (ERP) of the phantom to the liquid top surface is larger than 15 cm, which is shown in Fig. 6.1. For body SAR testing, the liquid height from the center of the flat phantom to the liquid top surface is larger than 15 cm, which is shown as followed:



Photo of Liquid Height for Body SAR

Frequency	Water	Sugar	Cellulose	Salt	Preventol	DGBE	Conductivity	Permittivity				
(MHz)	(%)	(%)	(%) (%)		(%) (%)		(σ)	(er)				
For Head												
900	40.3	57.9	0.2	1.4	0.2	0.nbot	0.97	41.5				
1750	55.2	0	0	0.3	0 bote	44.5	1.37	40.1				
1800,1900,2000	55.2	0 tek	Opotek	0.3	0	44.5	1.40	40.0				
2450	55.0	0	K 0 probots	0 Proto	0	45.0	1.80	39.2				
2600	54.8	0	oter 0 pot	0.1	0	45.1	1.96	39.0				
5000	65.5	0	17.2	0	17.3	0 pote	5.27	35.3				
5000	78.6	0	10.7	0	10.7	0	6.00	48.2				

The following table gives the recipes for tissue simulating liquid.

Shenzhen Anbotek Compliance Laboratory Limited

Address: 1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 755-26066440 Fax: (86) 755-26014772 Email: service@anbotek.com

Anbotek Product Safety

Report No.: 18220WC00163202 FCC ID: 2AV3G-TX12 The following table shows the measuring results for simulating liquid.

Page 20 of 62

Measured	ed Target Tissue		Measured Tissue				Liquid	
Frequency (MHz)	٤r	σ	٤r	Dev. (%)	σ	Dev. (%)	Liquid Temp.	Test Date
2450	39.2	1.80	39.48	0.71	1.82	1.11 pm	22.4	11/23/2020

Shenzhen Anbotek Compliance Laboratory Limited

Address: 1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 755–26066440 Fax: (86) 755–26014772 Email: service@anbotek.com

Anbotek

Product Safety

FCC ID: 2AV3G-TX12

Page 21 of 62

7. System Verification Procedures

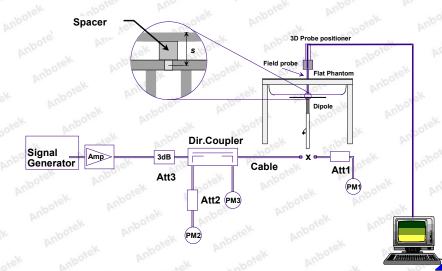
Each DASY system is equipped with one or more system validation kits. These units, together with the predefined measurement procedures within the DASY software, enable the user to conduct the system performance check and system validation. System validation kit includes a dipole, tripod holder to fix it underneath the flat phantom and a corresponding distance holder.

Purpose of System Performance check

The system performance check verifies that the system operates within its specifications. System and operator errors can be detected and corrected. It is recommended that the system performance check be performed prior to any usage of the system in order to guarantee reproducible results. The system performance check uses normal SAR measurements in a simplified setup with a well characterized source. This setup was selected to give a high sensitivity to all parameters that might fail or vary over time. The system check does not intend to replace the calibration of the components, but indicates situations where the system uncertainty is exceeded due to drift or failure.

System Setup

In the simplified setup for system evaluation, the EUT is replaced by a calibrated dipole and the power source is replaced by a continuous wave that comes from a signal generator. The calibrated dipole must be placed beneath the flat phantom section of the SAM twin phantom with the correct distance holder. The distance holder should touch the phantom surface with a light pressure at the reference marking and be oriented parallel to the long side of the phantom. The equipment setup is shown below:



System Setup for System Evaluation

Shenzhen Anbotek Compliance Laboratory Limited

Address: 1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 755–26066440 Fax: (86) 755–26014772 Email: service@anbotek.com



FCC ID: 2AV3G-TX12

Page 22 of 62



Photo of Dipole Setup

Validation Results

Comparing to the original SAR value provided by SPEAG, the verification data should be within its specification of 10%. The table below shows the target SAR and measured SAR after normalized to 1W input power. It indicates that the system performance check can meet the variation criterion and the plots can be referred to Appendix A of this report.

Frequency (MHz)	Power fed onto reference dipole (mW)	Targeted SAR (W/kg)	Measured SAR (W/kg)	Normalized SAR (W/kg)	Deviation (%)	Test Date
2450	250	24.3	6.15	24.60	1.23	11/23/2020

Target and Measurement SAR after Normalized

Shenzhen Anbotek Compliance Laboratory Limited



Anbotek

Product Safety

8. EUT Testing Position

8.1 Body Worn Position

Body-worn operating configurations are tested with the belt-clips and holsters attached to the device and positioned against a flat phantom in a normal use configuration. Per KDB 648474 D04, body-worn accessory exposure is typically related to voice mode operations when handsets are carried in body-worn accessories. The body-worn accessory procedures in FCC KDB 447498 D01 v06, 2015 should be used to test for body-worn accessory SAR compliance, without a headset connected to it. This enables the test results for such configuration to be compatible withthat required for hotspot mode when the body-worn accessory test separation distance is greater than or equal to that required for hotspot mode, when applicable. When the reported SAR for body-worn accessory, measured without a headset connected to the handset is < 1.2 W/kg, the highest reported SAR configuration for that wireless mode and frequency band should be repeated for that body-worn accessory with a handset attached to the handset.

Accessories for body-worn operation configurations are divided into two categories: those that do not contain metallic components and those that do contain metallic components. When multiple accessories that do not contain metallic components are supplied with the device, the device is tested with only the accessory that dictates the closest spacing to the body. Then multiple accessories that contain metallic components are test with the device with each accessory. If multiple accessories share an identical metallic component (i.e. the same metallic belt-chip used with different holsters with no other metallic components) only the accessory that dictates the closest spacing to the body is tested.

motherd tera

Body Worn Position

Shenzhen Anbotek Compliance Laboratory Limited

motherd tely





Anbotek

Product Safety

FCC ID: 2AV3G-TX12 Page 24 of 62

9. Measurement Procedures

The measurement procedures are as follows:

- (a) Use base station simulator (if applicable) or engineering software to transmit RF power continuously (continuous Tx) in the middle channel.
- (b) Keep EUT to radiate maximum output power or 100% duty factor (if applicable)
- (c) Measure output power through RF cable and power meter.
- (d) Place the EUT in the positions as setup photos demonstrates.
- (e) Set scan area, grid size and other setting on the DASY software.
- (f) Measure SAR transmitting at the middle channel for all applicable exposure positions.
- (g) Identify the exposure position and device configuration resulting the highest SAR
- (h) Measure SAR at the lowest and highest channels at the worst exposure position and device configuration if applicable.

According to the test standard, the recommended procedure for assessing the peak spatial-average SAR value consists of the following steps:

- (a) Power reference measurement
- (b) Area scan
- (c) Zoom scan
- (d) Power drift measurement

9.1 Spatial Peak SAR Evaluation

The procedure for spatial peak SAR evaluation has been implemented according to the test standard. It can be conducted for 1g and 10g, as well as for user-specific masses. The DASY software includes all numerical procedures necessary to evaluate the spatial peak SAR value.

The base for the evaluation is a "cube" measurement. The measured volume must include the 1g and 10g cubes with the highest averaged SAR values. For that purpose, the center of the measured volume is aligned to the interpolated peak SAR value of a previously performed area scan.

The entire evaluation of the spatial peak values is performed within the post-processing engine (SEMCAD). The system always gives the maximum values for the 1g and 10g cubes. The algorithm to find the cube with highest averaged SAR is divided into the following stages:

- (a) Extraction of the measured data (grid and values) from the Zoom Scan
- (b) Calculation of the SAR value at every measurement point based on all stored data (A/D values and measurement parameters)
- (c) Generation of a high-resolution mesh within the measured volume
- (d) Interpolation of all measured values form the measurement grid to the high-resolution grid
- (e) Extrapolation of the entire 3-D field distribution to the phantom surface over the distance from

Shenzhen Anbotek Compliance Laboratory Limited

Anbotek Product Safety

Report No.: 18220WC00163202

FCC ID: 2AV3G-TX12

Page 25 of 62

- sensor to surface
- (f) Calculation of the averaged SAR within masses of 1g and 10g

9.2 Power Reference Measurement

The Power Reference Measurement and Power Drift Measurements are for monitoring the power drift of the device under test in the batch process. The minimum distance of probe sensors to surface determines the closest measurement point to phantom surface. This distance cannot be smaller than the distance of sensor calibration points to probe tip as defined in the probe properties.

9.3 Area Scan Procedures

The area scan is used as a fast scan in two dimensions to find the area of high field values, before doing a fine measurement around the hot spot. The sophisticated interpolation routines implemented in DASY software can find the maximum found in the scanned area, within a range of the global maximum. The range (in dB0 is specified in the standards for compliance testing. For example, a 2 dB range is required in IEEE standard 1528 and IEC 62209 standards, whereby 3 dB is a requirement when compliance is assessed in accordance with the ARIB standard (Japan), if only one zoom scan follows the area scan, then only the absolute maximum will be taken as reference. For cases where multiple maximums are detected, the number of zoom scans has to be increased accordingly.

Area scan parameters extracted from FCC KDB 865664 D01 SAR measurement 100 MHz to 6 GHz.

10° 10° 10°	7.0.4	26* 1' 0		
	\leq 3 GHz	> 3 GHz		
Maximum distance from closest measurement point (geometric center of probe sensors) to phantom surface	$5 \pm 1 \text{ mm}$	$\frac{1}{2} \cdot \delta \cdot \ln(2) \pm 0.5 \text{ mm}$		
Maximum probe angle from probe axis to phantom surface normal at the measurement location	$30^{\circ} \pm 1^{\circ}$	$20^{\circ} \pm 1^{\circ}$		
	\leq 2 GHz: \leq 15 mm 2 - 3 GHz: \leq 12 mm	$3 - 4 \text{ GHz:} \le 12 \text{ mm}$ $4 - 6 \text{ GHz:} \le 10 \text{ mm}$		
Maximum area scan spatial resolution: Δx_{Area} , Δy_{Area}	When the x or y dimension of the test device, in the measurement plane orientation, is smaller than the above, the measurement resolution must be \leq the corresponding x or y dimension of the test device with at least one measurement point on the test device.			

Shenzhen Anbotek Compliance Laboratory Limited

FCC ID: 2AV3G-TX12

Page 26 of 62

9. 4 Zoom Scan Procedures

Report No.: 18220WC00163202

Zoom scans are used assess the peak spatial SAR values within a cubic averaging volume containing 1 gram and 10gram of simulated tissue. The zoom scan measures points (refer to table below) within a cube shoes base faces are centered on the maxima found in a preceding area scan job within the same procedure. When the measurement is done, the zoom scan evaluates the averaged SAR for 1 gram and 10 gram and displays these values next to the job's label. Zoom scan parameters extracted from FCC KDB 865664 D01 SAR measurement 100 MHz to 6 GHz.

			\leq 3 GHz	> 3 GHz		
at store	Dur	v	And Lak	por pris		
		lutions Am Am	\leq 2 GHz: \leq 8 mm	$3 - 4 \text{ GHz} \le 5 \text{ mm}^*$		
Maximum zoom scan s	spatial resc	plution: Δx_{Zoom} , Δy_{Zoom}	$2 - 3$ GHz: ≤ 5 mm [*]	$4 - 6 \text{ GHz} \le 4 \text{ mm}^*$		
				$3 - 4$ GHz: ≤ 4 mm		
	uniform	grid: $\Delta z_{Zoom}(n)$	\leq 5 mm	$4-5$ GHz: ≤ 3 mm		
				$5 - 6 \text{ GHz}: \le 2 \text{ mm}$		
Maximum zoom scan		$\Delta z_{Zoom}(1)$: between		$3 - 4$ GHz: ≤ 3 mm		
spatial resolution,		1 st two points closest to phantom surface	\leq 4 mm	$4-5$ GHz: ≤ 2.5 mm		
normal to phantom surface	graded			$5-6~GHz$: $\leq 2~mm$		
	grid $\Delta z_{Zoom}(n>1)$: between subsequent points		$\leq 1.5 \cdot \Delta z_{Zoom}(n-1)$			
				3 – 4 GHz: ≥ 28 mm		
Minimum zoom scan	x, y, z		\geq 30 mm	$4 - 5$ GHz: ≥ 25 mm		
volume				5 – 6 GHz: ≥ 22 mm		

Note: δ is the penetration depth of a plane-wave at normal incidence to the tissue medium; see draft standard IEEE P1528-2011 for details.

When zoom scan is required and the <u>reported</u> SAR from the area scan based 1-g SAR estimation procedures of KDB 447498 is ≤ 1.4 W/kg, ≤ 8 mm, ≤ 7 mm and ≤ 5 mm zoom scan resolution may be applied, respectively, for 2 GHz to 3 GHz, 3 GHz to 4 GHz and 4 GHz to 6 GHz.

Shenzhen Anbotek Compliance Laboratory Limited



FCC ID: 2AV3G-TX12

Page 27 of 62

9.5 Volume Scan Procedures

The volume scan is used for assess overlapping SAR distributions for antennas transmitting in different frequency bands. It is equivalent to an oversized zoom scan used in standalone measurements. The measurement volume will be used to enclose all the simultaneous transmitting antennas. For antennas transmitting simultaneously in different frequency bands, the volume scan is measured separately in each frequency band. In order to sum correctly to compute the 1g aggregateSAR, the EUT remain in the same test position for all measurements and all volume scan use the same spatial resolution and grid spacing. When all volume scan were completed, the software, SEMCAD postprocessor can combine and subsequently superpose these measurement data to calculating the multiband SAR.

9.6 Power Drift Monitoring

All SAR testing is under the EUT install full charged battery and transmit maximum output power. In DASY measurement software, the power reference measurement and power drift measurement procedures are used for monitoring the power drift of EUT during SAR test. Both these procedures measure the field at a specified reference position before and after the SAR testing. The software will calculate the field difference in dB. If the power drift more than 5%, the SAR will be retested.

Shenzhen Anbotek Compliance Laboratory Limited

Address: 1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 755–26066440 Fax: (86) 755–26014772 Email: service@anbotek.com



Report No.: 18220WC00163202 FCC ID: 2AV3G-TX12 Page 28 of 62

10. Conducted Power

<2.4GHz Conducted Power>

Mode	Frequency (MHz)	Conducted Output Power(Peak, dBm)
	2416	17.601
GFSK	2440	17.582
	2466	17.370

Note:

1. Per KDB 447498 D01 v06, 2015, the test distance less than 5mm

Frequency (MHz)			Max. Power (mW)	Test distance (mm)	Result	exclusion thresholds for 1-g SAR	
2416	17.601	18 pril	63.10	otek 5 unbo	19.616	3.0	

Base on the result of note1, RF exposure evaluation of 2.4GTX mode is required.

2. Per KDB 248227 D01, choose the highest output power channel to test SAR and determine further SAR exclusion.

3. Per KDB 248227 D01, In the 5GHz band, separate SAR procedures are applied to DSSS and OFDM configurations to simplify DSSS test requirements. SAR is not required for the following 5GHz OFDM conditions:

1) When KDB Publication 447498 SAR test exclusion applies to the OFDM configuration.

2) When the highest reported SAR for DSSS is adjusted by the ratio of OFDM to DSSS specified maximum output power and the adjusted SAR is \leq 1.2 W/kg.

Shenzhen Anbotek Compliance Laboratory Limited



Anbotek **Product Safety**

150mm

Report No.: 18220WC00163202 FCC ID: 2AV3G-TX12 Page 29 of 62

Antenna Location

2.4G TX/BT ANT, _

150mm 70mm 70mm **EUT Right Edge EU**

EUT Top Edge

Left Edge EU EUT

EUT Bottom Edge

EUT BACK VIEW

Distance of The Antenna to the EUT surface and edge										
Antennas Front Back Top Side Bottom Side Left Side Right Side										
2.4G	<25mm	<25mm	<25mm	>25mm	>25mm	>25mm				
and	Lett.	,b01	bro. N	hoten Anbi		ok bor				

Positions for SAR tests; Hotspot mode									
Antennas Front Back Top Side Bottom Side Left Side Right Side									
2.4G Yes		Yes	Yes	No otek	Anto No	No No			

General Note: Referring to KDB 941225 D06, When the overall device length and width are ≥9cm*5cm, the test distance is 0mm, SAR must be measured for all sides and surfaces with a transmitting antenna located with 25mm from that surface or edge.

Shenzhen Anbotek Compliance Laboratory Limited



FCC ID: 2AV3G-TX12

Page 30 of 62

11. SAR Test Results Summary

General Note:

 Per KDB 447498 D01 v06, 2015, the reported SAR is the measured SAR value adjusted for maximum tune-up tolerance.

Scaling Factor = tune-up limit power (mW) / EUT RF power (mW), where tune-up limit is the maximum rated power among all production units.

Reported SAR(W/kg)= Measured SAR(W/kg)* Scaling Factor

- 2. Per KDB 447498 D01v05r01, for each exposure position, if the highest output channel reported SAR≤0.8W/kg, other channels SAR testing are not necessary
- 3. Per KDB 941225 D05, start with the largest channel bandwidth and measure SAR for QPSK with 1 RB allocation, using the RB offset and required test channel combination with the highest maximum output power for RB offsets at the upper edge, middle and lower edge of each required test channel.
- Per KDB 941225 D05, 50% RB allocation for QPSK SAR testing follows 1RB QPSK allocation procedure.
 Des KDB 041225 D05, For QDSK with 100% RB allocation. SAB is not required when the histoart
- 5. Per KDB 941225 D05, For QPSK with 100% RB allocation, SAR is not required when the highest maximum output power for 100 % RB allocation is less than the highest maximum output power in 50% and 1 RB allocations and the highest reported SAR for 1 RB and 50% RB allocation are ≤ 0.8 W/kg. Otherwise, SAR is measured for the highest output power channel; and if the reported SAR is > 1.45 W/kg, the remaining required test channels must also be tested.
- Per KDB 941225 D05, 16QAM output power for each RB allocation configuration is > not ½ dB higher than the same configuration in QPSK and the reported SAR for the QPSK configuration is ≤ 1.45 W/kg; Per KDB 941225 D05, 16QAM SAR testing is not required.
- 7. Per KDB 941225 D05, Smaller bandwidth output power for each RB allocation configuration is > not ½ dB higher than the same configuration in the largest supported bandwidth, and the reported SAR for the largest supported bandwidth is ≤ 1.45 W/kg; Per KDB 941225 D05, smaller bandwidth SAR testing is not required.
- Per KDB865664 D01, for each frequency band, repeated SAR measurement is required only when the measured SAR is ≥0.8W/Kg; if the deviation among the repeated measurement is ≤20%,and the measured SAR <1.45W/Kg, only one repeated measurement is required.

Body SAR Results

Plo No	Band	Test Position	Gap (cm)		Average Power (dBm)	Tune-Up Limit (dBm)	Scaling Factor	Drift	Measured SAR _{1g} (W/kg)	Reported SAR _{1g} (W/kg)
#1	2.4G TX	Front	0	2416	17.061	18	1.055	-0.05	0.204	0.215
	2.4G TX	Back	0	2416	17.061	18	1.055	0.10	0.099	0.104
de la	2.4G TX	Left Side	0	2416	N/A	N/A	N/A	N/A	N/A	N/A
Hotek	2.4G TX	Right Side	0	2416	N/A	N/A	N/A	N/A	N/A	N/A
#2	2.4G TX	Top Side	0	2416	17.061	18	1.055	0.12	0.386	0.407
nup.	2.4G TX	Bottom Side	0	2416	N/A	N/A	N/A	N/A	N/A	N/A

< 2.4GHz>

Shenzhen Anbotek Compliance Laboratory Limited

Address: 1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 755–26066440 Fax: (86) 755–26014772 Email: service@anbotek.com



FCC ID: 2AV3G-TX12

Page 31 of 62

12. Simultaneous Transmission Analysis

Simultaneous TX SAR Considerations

No.		Applicable	Simultar	neous Transm	nission			
	. Jooter	N/A MO	V.	Lotek	Anbort	Prin	xet	abot

Evaluation of Simultaneous SAR

N/A

Shenzhen Anbotek Compliance Laboratory Limited





13. Measurement Uncertainty

PerKDB865664D01 SAR Measurement 100MHz to 6GHz, when the highest measured 1-gSAR within a frequency band is<1.5W/Kg, the extensive SAR measurement uncertain tyanalys is described in IEC 62209-2:2010 is not required in SAR reports submitted for equipment approval.

Shenzhen Anbotek Compliance Laboratory Limited

Address: 1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 755–26066440 Fax: (86) 755–26014772 Email: service@anbotek.com



FCC ID: 2AV3G-TX12

Page 33 of 62

Appendix A. EUT Photos and Test Setup Photos



Body Front (0mm)





Body Top (0mm)

Shenzhen Anbotek Compliance Laboratory Limited

Address: 1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 755–26066440 Fax: (86) 755–26014772 Email: service@anbotek.com



Anbotek

Product Safety

Appendix B. Plots of SAR System Check

2450MHz Head System Check

DUT: Dipole 2450 MHz; Type: D2450V2; Serial: D2450V2 - SN:910 Communication System: UID 0, CW; Frequency: 2450 MHz;Duty Cycle: 1:1 Medium parameters used: f = 2450 MHz; σ = 1.82 S/m; ϵ_r = 39.48; ρ = 1000 kg/m³ Phantom section: Flat Section

DASY5 Configuration:

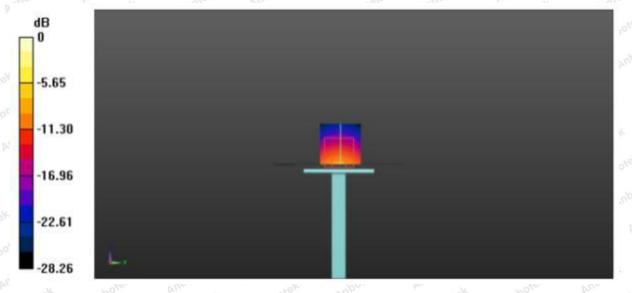
- Probe: EX3DV4 SN7396; ConvF(7.57, 7.57, 7.57); Calibrated: May,06.2020;
- Sensor-Surface: 2mm (Mechanical Surface Detection)
- Electronics: DAE4 Sn387; Calibrated: Sep.06.2020
- Phantom: SAM; Type: QD000P40CD; Serial: TP:1670
- Measurement SW: DASY52, Version 52.8 (2); SEMCAD X Version 14.6.10 (7164)

Configuration/Pin=250mW/Area Scan (81x81x1):Interpolated grid: dx=1.200 mm, dy=1.200 mm Maximum value of SAR (interpolated) = 20.36 W/kg

Configuration/Pin=250mW/Zoom Scan (7x7x7)/Cube 0:Measurement grid: dx=5mm, dy=5mm, dz=5mm

Reference Value = 87.825 V/m; Power Drift = 0.05 dB Peak SAR (extrapolated) = 26.71 W/kg SAR(1 g) = 12.83 W/kg; SAR(10 g) = 6.15 W/kg

Maximum value of SAR (measured) = 19.48 W/kg



Shenzhen Anbotek Compliance Laboratory Limited

Address: 1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 755–26066440 Fax: (86) 755–26014772 Email: service@anbotek.com



Appendix C. Plots of SAR Test Data

#1

Date: 2020-11-23

2.4G TX_Body Front _2416MHz

Communication System: UID 0, 2.4G TX (fcc) (0); Frequency: 2416 MHz; Duty Cycle: 1:1 Medium parameters used (interpolated): f = 2416 MHz; $\sigma = 1.82$ S/m; $\varepsilon_r = 39.48$; $\rho = 1000$ kg/m³ Phantom section: Flat Section

DASY5 Configuration:

- Probe: EX3DV4 SN7396; ConvF(8.14, 8.14, 8.14); Calibrated: May,06.2020;
- Sensor-Surface: 2mm (Mechanical Surface Detection)
- Electronics: DAE4 Sn387; Calibrated: Sep.06,2020
- Phantom: SAM; Type: QD000P40CD; Serial: TP:1670
- Measurement SW: DASY52, Version 52.8 (2); SEMCAD X Version 14.6.10 (7164)

BODY/EARPHONE-H/Area Scan (8x13x1): Measurement grid: dx=10mm, dy=10mm

Maximum value of SAR (measured) = 0.234 W/kg

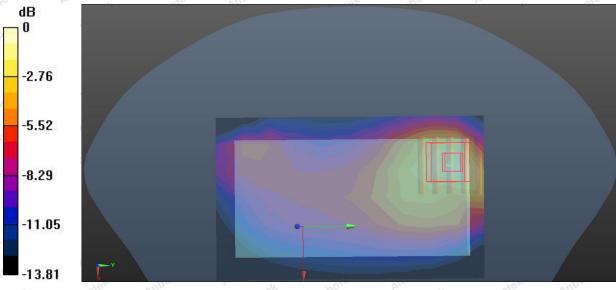
Configuration/BACK/Zoom Scan (7x7x7)/Cube 0: Measurement grid: dx=5mm, dy=5mm, dz=5mm

Reference Value = 10.84V/m; Power Drift =-0.05 dB

Peak SAR (extrapolated) = 0.224 W/kg

SAR(1 g) = 0.204W/kg; SAR(10 g) = 0.108 W/kg

Maximum value of SAR (measured) = 0.215 W/kg



Shenzhen Anbotek Compliance Laboratory Limited

Address: 1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 755–26066440 Fax: (86) 755–26014772 Email: service@anbotek.com

Anbotek Product Safety

Report No.: 18220WC00163202

FCC ID: 2AV3G-TX12 F

Page 36 of 62

#2

Date: 2020-11-23 2.4G TX Body Top 2416MHz

Communication System: UID 0, 2.4G TX (fcc) (0); Frequency: 2416 MHz;Duty Cycle: 1:1 Medium parameters used (interpolated): f = 2416 MHz; $\sigma = 1.82$ S/m; $\epsilon_r = 39.48$; $\rho = 1000$ kg/m³ Phantom section: Flat Section

DASY5 Configuration:

- Probe: EX3DV4 SN7396; ConvF(8.14, 8.14, 8.14); Calibrated: May,06.2020;
- Sensor-Surface: 2mm (Mechanical Surface Detection)
- Electronics: DAE4 Sn387; Calibrated: Sep. 06,2020
- Phantom: SAM; Type: QD000P40CD; Serial: TP:1670
- Measurement SW: DASY52, Version 52.8 (2); SEMCAD X Version 14.6.10 (7164)

BODY/EARPHONE-H/Area Scan (8x13x1): Measurement grid: dx=10mm, dy=10mm Maximum value of SAR (measured) = 0.397 W/kg

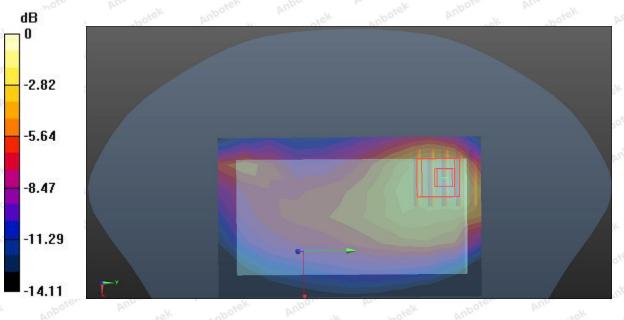
Configuration/BACK/Zoom Scan (7x7x7)/Cube 0: Measurement grid: dx=5mm, dy=5mm, dz=5mm

Reference Value = 12.86 V/m; Power Drift = 0.12 dB

Peak SAR (extrapolated) = 0.398 W/kg

SAR(1 g) = 0.386 W/kg; SAR(10 g) = 0.214 W/kg

Maximum value of SAR (measured) = 0.418 W/kg



Shenzhen Anbotek Compliance Laboratory Limited

Address: 1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 755–26066440 Fax: (86) 755–26014772 Email: service@anbotek.com



Certificate No: Z20-68716

Page 1 of 11

Shenzhen Anbotek Compliance Laboratory Limited

Address: 1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 755–26066440 Fax: (86) 755–26014772 Email: service@anbotek.com

Anbotek

Product Safety



E-mail: ettl it chinattl.com

Add: No.51 Xueyuan Road, Haidian District, Beijing, 100191, China Tel: +86-10-62304633-2218 Fax: +86-10-62304633-2209 Http://www.chinattl.cn

Glossary:

TSL	tissue simulating liquid
NORMx,y,z	sensitivity in free space
ConvF	sensitivity in TSL / NORMx,y,z
DCP	diode compression point
CF	crest factor (1/duty_cycle) of the RF signal
A,B,C,D	modulation dependent linearization parameters
Polarization Φ	Φ rotation around probe axis
Polarization 0	θ rotation around an axis that is in the plane normal to probe axis (at measurement center), i θ=0 is normal to probe axis

Connector Angle information used in DASY system to align probe sensor X to the robot coordinate system Calibration is Performed According to the Following Standards:

FCC ID: 2AV3G-TX12

- a) IEEE Std 1528-2013. "IEEE Recommended Practice for Determining the Peak Spatial-Averaged Specific Absorption Rate (SAR) in the Human Head from Wireless Communications Devices: Measurement Techniques", June 2013
- b) IEC 62209-1, "Procedure to measure the Specific Absorption Rate (SAR) for hand-held devices used in close proximity to the ear (frequency range of 300MHz to 3GHz)", February 2005
- c) IEC 62209-2, "Procedure to determine the Specific Absorption Rate (SAR) for wireless communication devices used in close proximity to the human body (frequency range of 30 MHz to 6 GHz)", March 2010

d) KDB 865664, "SAR Measurement Requirements for 100 MHz to 6 GHz"

Methods Applied and Interpretation of Parameters:

- NORMx, y.z: Assessed for E-field polarization θ=0 (f≤900MHz in TEM-cell; f>1800MHz; waveguide). NORMx,y,z are only intermediate values, i.e., the uncertainties of NORMx,y,z does not effect the E²-field uncertainty inside TSL (see below ConvF).
- NORM(I)x, y, z = NORMx, y, z* frequency_response (see Frequency Response Chart). This linearization is implemented in DASY4 software versions later than 4.2. The uncertainty of the frequency response is included in the stated uncertainty of ConvF.
- DCPx, y.z: DCP are numerical linearization parameters assessed based on the data of power sweep (no uncertainty required). DCP does not depend on frequency nor media.
- PAR: PAR is the Peak to Average Ratio that is not calibrated but determined based on the signal characteristics.
- Ax,y,z; Bx,y,z; Cx,y,z; VRx,y,z;A,B,C are numerical linearization parameters assessed based on the data of power sweep for specific modulation signal. The parameters do not depend on frequency nor media. VR is the maximum calibration range expressed in RMS voltage across the diode.
- ConvF and Boundary Effect Parameters: Assessed in flat phantom using E-field (or Temperature Transfer Standard for f≤800MHz) and inside waveguide using analytical field distributions based on power measurements for f >800MHz. The same setups are used for assessment of the parameters applied for boundary compensation (alpha, depth) of which typical uncertainty valued are given. These parameters are used in DASY4 software to improve probe accuracy close to the boundary. The sensitivity in TSL corresponds to NORMx,y,z* ConvF whereby the uncertainty corresponds to that given for ConvF. A frequency dependent ConvF is used in DASY version 4.4 and higher which allows extending the validity from±50MHz to±100MHz.
- Spherical isotropy (3D deviation from isotropy): in a field of low gradients realized using a flat phantom exposed by a patch antenna.
- Sensor Offset: The sensor offset corresponds to the offset of virtual measurement center from the probe tip (on probe axis). No tolerance required.
- Connector Angle: The angle is assessed using the information gained by determining the NORMx (no uncertainty required).

Certificate No: Z20-68716

Page 2 of 11

Shenzhen Anbotek Compliance Laboratory Limited

Address: 1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 755-26066440 Fax: (86) 755-26014772 Email: service@anbotek.com

Hotline 400-003-0500 www.anbotek.com

Page 38 of 62





Page 39 of 62



Add: No.51 Xueyuan Road, Tel: +86-10-62304633-2218 E-mail: cttl@chinattl.com

an Road, Haidian District, Beijing, 100191, China 533-2218 Fax: +86-10-62304633-2209 tl.com <u>Http://www.chinattl.cn</u>

Probe EX3DV4

SN: 7396

Calibrated: May 06, 2020

Calibrated for DASY/EASY Systems (Note: non-compatible with DASY2 system!)

Certificate No: Z20-68716

Page 3 of 11

Shenzhen Anbotek Compliance Laboratory Limited

Address: 1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 755–26066440 Fax: (86) 755–26014772 Email: service@anbotek.com

Anbote

Product Safety







Tel: +86-10-62304633-2218 E-mail: ettl@chinattl.com dian District, Beijing, 100191, China Fax: +86-10-62304633-2209 Http://www.chinattl.cn

DASY/EASY – Parameters of Probe: EX3DV4 – SN: 7396

Basic Calibration Parameters

	Sensor X	Sensor Y	Sensor Z	Unc (k=2)
Norm(µV/(V/m)2) ^A	0.54	0.53	0.50	±10.0%
DCP(mV) ^B	97.8	104.5	102.5	

Modulation Calibration Parameters

UID	Communication System Name		A dB	B dBõV	c	D dB	VR mV	Unc ^E (k=2)
0	CW	x	0.0	0.0	1.0	0.00	199.9	±2.4%
	100000	Y	0.0	0.0	1.0		203.3	
		Z	0.0	0.0	1.0		195.0	

The reported uncertainty of measurement is stated as the standard uncertainty of Measurement multiplied by the coverage factor k=2, which for a normal distribution Corresponds to a coverage probability of approximately 95%.

^A The uncertainties of Norm X, Y, Z do not affect the E²-field uncertainty inside TSL (see Page 5 and Page 6). ^B Numerical linearization parameter: uncertainty not required.

^E Uncertainly is determined using the max, deviation from linear response applying rectangular distribution and is expressed for the square of the field value.

Certificate No: Z20-68716

Page 4 of 11

Shenzhen Anbotek Compliance Laboratory Limited

Address: 1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 755–26066440 Fax: (86) 755–26014772 Email: service@anbotek.com

Anbote

Product Safety

FCC ID: 2AV3G-TX12





Tel: +86-10-62304633-2218 E-mail: ettl@chinattLcom

d, Haidian District, Beijing, 100191, China 18 Fax: +86-10-62304633-2209 Http://www.chinanl.cn

DASY/EASY – Parameters of Probe: EX3DV4 – SN: 7396

Calibration Parameter Determined in Head Tissue Simulating Media

f [MHz] ^C	Relative Permittivity ^F	Conductivity (S/m) ^F	ConvF X	ConvF Y	ConvF Z	Alpha ^G	Depth ^G (mm)	Unct. (k=2)
750	41.9	0.89	9.82	9.82	9.82	0.30	0.85	±12.1%
835	41.5	0.90	9.71	9.71	9.71	0.15	1.36	±12.1%
900	41.5	0.97	9.87	9.87	9.87	0.16	1.37	±12.1%
1750	40.1	1.37	8.61	8.61	8.61	0.25	1.04	±12.1%
1900	40.0	1.40	8.13	8.13	8.13	0.24	1.01	±12.1%
2100	39.8	1.49	8.14	8.14	8.14	0.24	1.04	±12.1%
2300	39.5	1.67	7.85	7.85	7.85	0.40	0.75	±12.1%
2450	39.2	1.80	7.57	7.57	7.57	0.50	0.75	±12.1%
2600	39.0	1.96	7.38	7.38	7.38	0.64	0.68	±12.1%
5250	35.9	4.71	5.33	5.33	5.33	0.45	1.30	±13.3%
5600	35.5	5.07	4.89	4.89	4.89	0.45	1.35	±13.3%
5750	35.4	5.22	4.92	4.92	4.92	0.45	1.45	±13.3%

^C Frequency validity above 300 MHz of ±100MHz only applies for DASY v4.4 and higher (Page 2), else it is restricted to ±50MHz. The uncertainty is the RSS of ConvF uncertainty at calibration frequency and the uncertainty for the indicated frequency band. Frequency validity below 300 MHz is ± 10, 25, 40, 50 and 70 MHz for ConvF assessments at 30, 64, 128, 150 and 220 MHz respectively. Above 5 GHz frequency validity can be extended to ± 110 MHz.

^F At frequency below 3 GHz, the validity of tissue parameters (ϵ and σ) can be relaxed to ±10% if liquid compensation formula is applied to measured SAR values. At frequencies above 3 GHz, the validity of tissue parameters (ϵ and σ) is restricted to ±5%. The uncertainty is the RSS of the ConvF uncertainty for indicated target tissue parameters. ^G Alpha/Depth are determined during calibration. SPEAG warrants that the remaining deviation due to the boundary effect after compensation is always less than ± 1% for frequencies below 3 GHz and below ± 2% for the frequencies between 3-6 GHz at any distance larger than half the probe tip diameter from the boundary.

Certificate No: Z20-68716

Page 5 of 11

Shenzhen Anbotek Compliance Laboratory Limited

Address: 1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 755–26066440 Fax: (86) 755–26014772 Email: service@anbotek.com

Anbote

Product Safety

FCC ID: 2AV3G-TX12





Add: No.51 Xueyuan Road, Ha Tel: +86-10-62304633-2218 E-mail: ettl@chinattl.com

aidian District, Beijing, 100191, China Fax: +86-10-62304633-2209 <u>Http://www.chinattl.cn</u>

DASY/EASY – Parameters of Probe: EX3DV4 – SN: 7396

Calibration Parameter Determined in Body Tissue Simulating Media

f [MHz] ^C	Relative Permittivity ^F	Conductivity (S/m) ^F	ConvF X	ConvF Y	ConvF Z	Alpha ^G	Depth ^G (mm)	Unct. (k=2)
750	55.5	0.96	10.09	10.09	10.09	0.30	0.90	±12.1%
835	55.2	0.97	9.88	9.88	9.88	0.19	1.32	±12.1%
900	55.0	1.05	9.82	9.82	9.82	0.23	1.15	±12.1%
1750	53.4	1.49	8.24	8.24	8.24	0.24	1.06	±12.1%
1900	53.3	1.52	7.97	7.97	7.97	0.19	1.24	±12.1%
2100	53.2	1.62	8.18	8.18	8.18	0.19	1.39	±12.1%
2300	52.9	1.81	7.88	7.88	7.88	0.55	0.80	±12.1%
2450	52.7	1.95	7.53	7.53	7.53	0.46	0.89	±12.1%
2600	52.5	2.16	7.38	7.38	7.38	0.52	0.80	±12.1%
5250	48.9	5.36	4.93	4.93	4.93	0.45	1.80	±13.3%
5600	48.5	5.77	4.19	4.19	4.19	0.48	1.90	±13.3%
5750	48.3	5.94	4.52	4.52	4.52	0.48	1.95	±13.3%

^C Frequency validity above 300 MHz of ±100MHz only applies for DASY v4.4 and higher (Page 2), else it is restricted to ±50MHz. The uncertainty is the RSS of ConvF uncertainty at calibration frequency and the uncertainty for the indicated frequency band. Frequency validity below 300 MHz is ± 10, 25, 40, 50 and 70 MHz for ConvF assessments at 30, 64, 128, 150 and 220 MHz respectively. Above 5 GHz frequency validity can be extended to ± 110 MHz.

^F At frequency below 3 GHz, the validity of tissue parameters (ε and σ) can be relaxed to ±10% if liquid compensation formula is applied to measured SAR values. At frequencies above 3 GHz, the validity of tissue parameters (ε and σ) is restricted to ±5%. The uncertainty is the RSS of the ConvF uncertainty for indicated target tissue parameters. ^G Alpha/Depth are determined during calibration. SPEAG warrants that the remaining deviation due to the boundary effect after compensation is always less than ± 1% for frequencies below 3 GHz and below ± 2% for the frequencies between 3-6 GHz at any distance larger than half the probe tip diameter from the boundary.

Certificate No: Z20-68716

Page 6 of 11

Shenzhen Anbotek Compliance Laboratory Limited

Address: 1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 755–26066440 Fax: (86) 755–26014772 Email: service@anbotek.com

Anbote

Product Safety

FCC ID: 2AV3G-TX12

Page 43 of 62

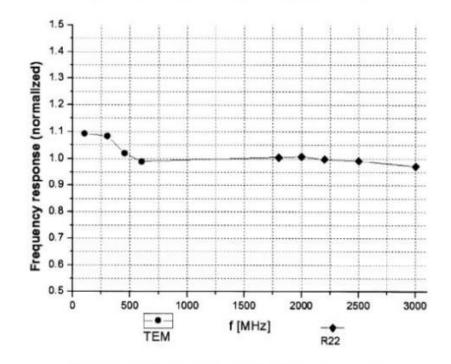


 Add: No.51 Xueyuan Road, Haidian District, Beijing, 100191, China

 Tel: +86-10-62304633-2218
 Fax: +86-10-62304633-2209

 E-mail: cttl@chinattl.com
 <u>Http://www.chinattl.cn</u>

Frequency Response of E-Field (TEM-Cell: ifi110 EXX, Waveguide: R22)





Certificate No: Z20-68716

Page 7 of 11

Shenzhen Anbotek Compliance Laboratory Limited

Address: 1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 755–26066440 Fax: (86) 755–26014772 Email: service@anbotek.com

Anbote

Product Safety



Page 44 of 62



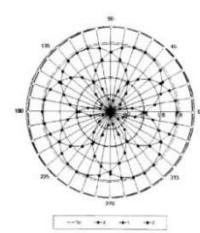
E-mail: ettl@chinattl.com

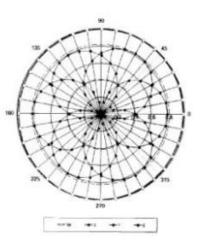
Add: No.51 Xueyuan Road, Haidian District, Beijing, 100191, China Tel: +86-10-62304633-2218 Fax: +86-10-62304633-2209 Http://www.chinattl.cn

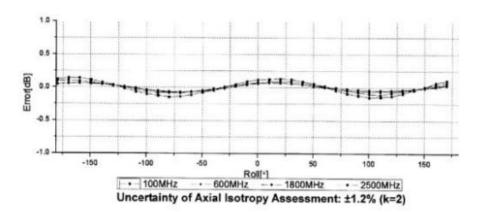
Receiving Pattern (Φ), θ=0°

f=600 MHz, TEM

f=1800 MHz, R22







Certificate No: Z20-68716

Page 8 of 11

Shenzhen Anbotek Compliance Laboratory Limited

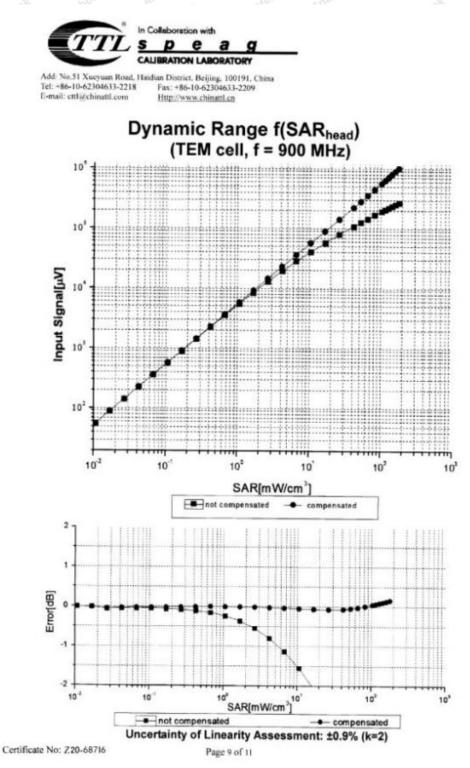
Address: 1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 755-26066440 Fax: (86) 755-26014772 Email: service@anbotek.com

Anbotek

Product Safety

FCC ID: 2AV3G-TX12





Shenzhen Anbotek Compliance Laboratory Limited

Address: 1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 755–26066440 Fax: (86) 755–26014772 Email: service@anbotek.com

Anbotek

Product Safety

FCC ID: 2AV3G-TX12





E-mail: ettl@chinattl.com Http://www.chinattl.cn

Conversion Factor Assessment

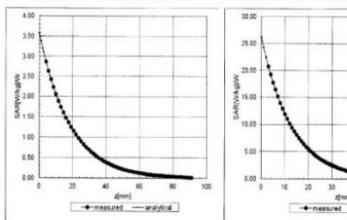
f=900 MHz, WGLS R9(H convF)

f=1750 MHz, WGLS R22(H_convF)

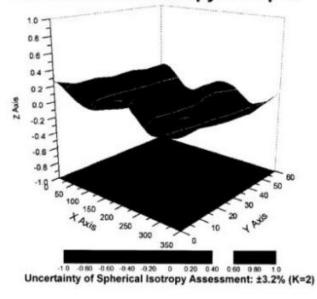
30 40

ż

-analytical







Certificate No: Z20-68716

Page 10 of 11

Shenzhen Anbotek Compliance Laboratory Limited

Address: 1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 755-26066440 Fax: (86) 755-26014772 Email: service@anbotek.com

Anbot

Product Safety

FCC ID: 2AV3G-TX12



Tel: +86-10-62304633-2218 Fax: +86-10-62304633-E-mail: ettl@chinattl.com Http://www.chinattl.com

DASY/EASY – Parameters of Probe: EX3DV4 – SN: 7396

Other Probe Parameters

Sensor Arrangement	Triangular
Connector Angle (°)	156.9
Mechanical Surface Detection Mode	enabled
Optical Surface Detection Mode	disable
Probe Overall Length	337mm
Probe Body Diameter	10mm
Tip Length	9mm
Tip Diameter	2.5mm
Probe Tip to Sensor X Calibration Point	1mm
Probe Tip to Sensor Y Calibration Point	1mm
Probe Tip to Sensor Z Calibration Point	1mm
Recommended Measurement Distance from Surface	1.4mm

Certificate No: Z20-68716

Page 11 of 11

Shenzhen Anbotek Compliance Laboratory Limited

Address: 1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 755–26066440 Fax: (86) 755–26014772 Email: service@anbotek.com



Schmid & Partner Engineering AG S P e a g

Zeughausstrasse 43, 8004 Zurich, Switzerland Phone +41 44 245 9700, Fax +41 44 245 9779 info@speag.com, http://www.speag.com

IMPORTANT NOTICE

USAGE OF THE DAE 4

The DAE unit is a delicate, high precision instrument and requires careful treatment by the user. There are no serviceable parts inside the DAE. Special attention shall be given to the following points:

Battery Exchange: The battery cover of the DAE4 unit is closed using a screw, over tightening the screw may cause the threads inside the DAE to wear out.

Shipping of the DAE: Before shipping the DAE to SPEAG for calibration, remove the batteries and pack the DAE in an antistatic bag. This antistatic bag shall then be packed into a larger box or container which protects the DAE from impacts during transportation. The package shall be marked to indicate that a fragile instrument is inside.

E-Stop Failures: Touch detection may be malfunctioning due to broken magnets in the E-stop. Rough handling of the E-stop may lead to damage of these magnets. Touch and collision errors are often caused by dust and dirt accumulated in the E-stop. To prevent E-stop failure, the customer shall always mount the probe to the DAE carefully and keep the DAE unit in a non-dusty environment if not used for measurements.

Repair: Minor repairs are performed at no extra cost during the annual calibration. However, SPEAG reserves the right to charge for any repair especially if rough unprofessional handling caused the defect.

DASY Configuration Files: Since the exact values of the DAE input resistances, as measured during the calibration procedure of a DAE unit, are not used by the DASY software, a nominal value of 200 MOhm is given in the corresponding configuration file.

Important Note:

Warranty and calibration is void if the DAE unit is disassembled partly or fully by the Customer.

Important Note:

Never attempt to grease or oil the E-stop assembly. Cleaning and readjusting of the Estop assembly is allowed by certified SPEAG personnel only and is part of the annual calibration procedure.

Important Note:

To prevent damage of the DAE probe connector pins, use great care when installing the probe to the DAE. Carefully connect the probe with the connector notch oriented in the mating position. Avoid any rotational movement of the probe body versus the DAE while turning the locking nut of the connector. The same care shall be used when disconnecting the probe from the DAE.

Schmid & Partner Engineering

TN_BR040315AD DAE4.doc

11.12.2009

Sh

Address: 1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 755–26066440 Fax: (86) 755–26014772 Email: service@anbotek.com



FCC ID: 2AV3G-TX12

Page 49 of 62

Calibration Laboratory of Schmid & Partner Engineering AG Zeughausstrasse 43, 8004 Zurich, Switzerland



S C S

Schweizerischer Kalibrierdienst Service suisse d'étalonnage Servizio svizzero di taratura Swiss Calibration Service

Accredited by the Swiss Accreditation Service (SAS) The Swiss Accreditation Service is one of the signatories to the EA Multilateral Agreement for the recognition of calibration certificates

Accreditation No.: SCS 0108

Object	DAE4 - SD 000 D		
Calibration procedure(s)	QA CAL-06.v29 Calibration procee	dure for the data acquisition elec	ctronics (DAE)
Calibration date:	September 06, 20	20	
Calibration Equipment used (M& Primary Standards	TE critical for calibration)	Cal Date (Certificate No.)	Scheduled Calibration
Keithley Multimeter Type 2001	SN: 0810278	15-Aug-20 (No:21092)	Aug-21
Secondary Standards	ID #	Check Date (in house)	Scheduled Check
Secondary Standards Auto DAE Calibration Unit	SE UWS 053 AA 1001	Check Date (in house) 05-Jan-20 (in house check) 05-Jan-20 (in house check)	
Secondary Standards Auto DAE Calibration Unit	SE UWS 053 AA 1001	05-Jan-20 (in house check)	Scheduled Check In house check: Jan-21
Secondary Standards Auto DAE Calibration Unit Calibrator Box V2.1	SE UWS 053 AA 1001 SE UMS 006 AA 1002 Name	05-Jan-20 (in house check) 05-Jan-20 (in house check) Function	Scheduled Check In house check: Jan-21
Secondary Standards Auto DAE Calibration Unit Calibrator Box V2.1	SE UWS 053 AA 1001 SE UMS 006 AA 1002	05-Jan-20 (in house check) 05-Jan-20 (in house check)	Scheduled Check In house check: Jan-21 In house check: Jan-21 Signature
Secondary Standards Auto DAE Calibration Unit Calibrator Box V2.1 Calibrated by:	SE UWS 053 AA 1001 SE UMS 006 AA 1002 Name	05-Jan-20 (in house check) 05-Jan-20 (in house check) Function	Scheduled Check In house check: Jan-21 In house check: Jan-21
Secondary Standards Auto DAE Calibration Unit Calibrator Box V2.1 Calibrated by: Approved by:	SE UWS 053 AA 1001 SE UMS 006 AA 1002 Name Dominique Steffen Sven Kühn	05-Jan-20 (in house check) 05-Jan-20 (in house check) Function Laboratory Technician	Scheduled Check In house check: Jan-21 In house check: Jan-21 Signature Model IN BAMM Issued: September 06, 2020

Address: 1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 755–26066440 Fax: (86) 755–26014772 Email: service@anbotek.com

Sh

400-003-0500 www.anbotek.com



FCC ID: 2AV3G-TX12

Page 50 of 62

Calibration Laboratory of Schmid & Partner Engineering AG Zeughausstrasse 43, 8004 Zurich, Switzerland





Schweizerischer Kalibrierdienst
 Service suisse d'étalonnage
 Servizio svizzero di taratura
 Swiss Calibration Service

Accreditation No.: SCS 0108

Accredited by the Swiss Accreditation Service (SAS) The Swiss Accreditation Service is one of the signatories to the EA Multilateral Agreement for the recognition of calibration certificates

Glossary

DAE Connector angle

data acquisition electronics

information used in DASY system to align probe sensor X to the robot coordinate system.

Methods Applied and Interpretation of Parameters

- *DC Voltage Measurement:* Calibration Factor assessed for use in DASY system by comparison with a calibrated instrument traceable to national standards. The figure given corresponds to the full scale range of the voltmeter in the respective range.
- *Connector angle*: The angle of the connector is assessed measuring the angle mechanically by a tool inserted. Uncertainty is not required.
- The following parameters as documented in the Appendix contain technical information as a
 result from the performance test and require no uncertainty.
 - DC Voltage Measurement Linearity: Verification of the Linearity at +10% and -10% of the nominal calibration voltage. Influence of offset voltage is included in this measurement.
 - Common mode sensitivity: Influence of a positive or negative common mode voltage on the differential measurement.
 - Channel separation: Influence of a voltage on the neighbor channels not subject to an input voltage.
 - AD Converter Values with inputs shorted: Values on the internal AD converter corresponding to zero input voltage
 - Input Offset Measurement: Output voltage and statistical results over a large number of zero voltage measurements.
 - Input Offset Current: Typical value for information; Maximum channel input offset current, not considering the input resistance.
 - Input resistance: Typical value for information: DAE input resistance at the connector, during internal auto-zeroing and during measurement.
 - Low Battery Alarm Voltage: Typical value for information. Below this voltage, a battery alarm signal is generated.
 - *Power consumption:* Typical value for information. Supply currents in various operating modes.

Certificate No: DAE4-387_Sep10

Page 2 of 5

Sh

Address: 1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 755–26066440 Fax: (86) 755–26014772 Email: service@anbotek.com Www.anbotek.com

FCC ID: 2AV3G-TX12

DC Voltage Measurement

A/D - Converter Reso	lution nominal			
High Range:	1LSB =	6.1µV,	full range =	-100+300 mV
Low Range:	1LSB =	61nV,	full range =	-1+3mV
DASY measurement	parameters: Aut	o Zero Time: 3	sec; Measuring	time: 3 sec

Calibration Factors	Х	Y	Z
High Range	404.489 ± 0.02% (k=2)	404.852 ± 0.02% (k=2)	404.862 ± 0.02% (k=2)
Low Range	3.97827 ± 1.50% (k=2)	3.95875 ± 1.50% (k=2)	

Connector Angle

Connector Angle to be used in DASY system	53.0 ° ± 1 °
	J 53.0 ± 1

Certificate No: DAE4-387_Sep10

Page 3 of 5



Address: 1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 755–26066440 Fax: (86) 755–26014772 Email: service@anbotek.com 400-003-0500 www.anbotek.com

FCC ID: 2AV3G-TX12

Appendix (Additional assessments outside the scope of SCS0108)

1. DC Voltage Linearity

High Range		Reading (µV)	Difference (µV)	Error (%)
Channel X	+ Input	200032.85	-3.31	-0.00
Channel X	+ Input	20007.64	1.88	0.01
Channel X	- Input	-20003.48	1.18	-0.01
Channel Y	+ Input	200034.23	-1.43	-0.00
Channel Y	+ Input	20006.60	0.91	0.00
Channel Y	- Input	-20004.04	0.72	-0.00
Channel Z	+ Input	200035.38	-0.83	-0.00
Channel Z	+ Input	20003.69	-2.11	-0.01
Channel Z	- Input	-20006.38	-1.59	0.01

Low Range	Reading (μV)	Difference (µV)	Error (%)
Channel X + Input	2001.63	0.08	0.00
Channel X + Input	202.29	0.70	0.35
Channel X - Input	-197.90	0.60	-0.30
Channel Y + Input	2001.33	-0.07	-0.00
Channel Y + Input	200.86	-0.60	-0.30
Channel Y - Input	-199.87	-1.23	0.62
Channel Z + Input	2001.61	0.27	0.01
Channel Z + Input	200.60	-0.70	-0.35
Channel Z - Input	-199.51	-0.85	0.43

2. Common mode sensitivity

DASY measurement parameters: Auto Zero Time: 3 sec; Measuring time: 3 sec

	Common mode Input Voltage (mV)	High Range Average Reading (μV)	Low Range Average Reading (μV)
Channel X	200	13.50	11.56
	- 200	-8.64	-11.18
Channel Y	200	-0.81	-1.28
	- 200	1.05	0.09
Channel Z	200	7.17	6.91
	- 200	-9.46	-9.01

3. Channel separation

DASY measurement parameters: Auto Zero Time: 3 sec; Measuring time: 3 sec

	Input Voltage (mV)	Channel X (μV)	Channel Y (µV)	Channel Z (µV)
Channel X	200	-	-1.70	0.33
Channel Y	200	10.70	-	-0.38
Channel Z	200	7.11	7.89	-

Certificate No: DAE4-387_Sep10

Page 4 of 5

Address: 1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 755–26066440 Fax: (86) 755–26014772 Email: service@anbotek.com

4. AD-Converter Values with inputs shorted

DASY measurement parameters: Auto Zero Time: 3 sec; Measuring time: 3 sec

	High Range (LSB)	Low Range (LSB)
Channel X	15969	17466
Channel Y	15661	16162
Channel Z	15990	16190

5. Input Offset Measurement

DASY measurement parameters: Auto Zero Time: 3 sec; Measuring time: 3 sec Input $10M\Omega$

	Average (μV)	min. Offset (μV)	max. Offset (μV)	Std. Deviation (µV)
Channel X	0.73	-2.58	3.29	0.62
Channel Y	0.41	-0.49	1.23	0.40
Channel Z	-0.80	-1.88	0.30	0.42

6. Input Offset Current

Nominal Input circuitry offset current on all channels: <25fA

7. Input Resistance (Typical values for information)

	Zeroing (kOhm)	Measuring (MOhm)
Channel X	200	200
Channel Y	200	200
Channel Z	200	200

8. Low Battery Alarm Voltage (Typical values for information)

Typical values	Alarm Level (VDC)
Supply (+ Vcc)	+7.9
Supply (- Vcc)	-7.6

9. Power Consumption (Typical values for information)

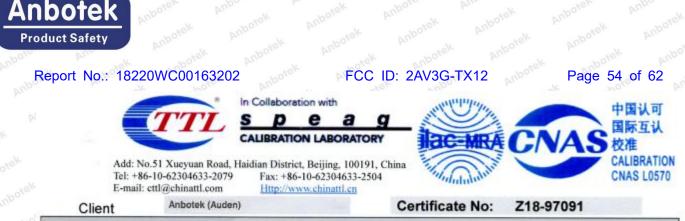
Typical values	Switched off (mA)	Stand by (mA)	Transmitting (mA)
Supply (+ Vcc)	+0.01	+6	+14
Supply (- Vcc)	-0.01	-8	-9

Certificate No: DAE4-387_Sep10

Page 5 of 5



Address: 1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 755–26066440 Fax: (86) 755–26014772 Email: service@anbotek.com 400-003-0500 www.anbotek.com



CALIBRATION CERTIFICATE

Object	D2450V2 - SN: 910
Calibration Procedure(s)	
Calibration rocedure(s)	FD-Z11-2-003-01
	Calibration Procedures for dipole validation kits
Calibration date:	Jun 15, 2018

This calibration Certificate documents the traceability to national standards, which realize the physical units of measurements(SI). The measurements and the uncertainties with confidence probability are given on the following pages and are part of the certificate.

All calibrations have been conducted in the closed laboratory facility: environment temperature(22±3)^{°C} and humidity<70%.

Calibration Equipment used (M&TE critical for calibration)

Primary Standards	ID #	Cal Date(Calibrated by, Certificate No.)	Scheduled Calibration
Power Meter NRP2	101919	01-Jul-17 (CTTL, No.J17X04256)	Jun-18
Power sensor NRP-Z91	101547	01-Jul-17 (CTTL, No.J17X04256)	Jun-18
Reference Probe EX3DV4	SN 7307	19-Feb-18(SPEAG,No.EX3-7307_Feb18)	Feb-19
DAE4	SN 771	02-Feb-18(CTTL-SPEAG,No.Z18-97011)	Feb-19
Secondary Standards	ID #	Cal Date(Calibrated by, Certificate No.)	Scheduled Calibration
Signal Generator E4438C	MY49071430	01-Feb-18 (CTTL, No.J18X00893)	Jan-19
Network Analyzer E5071C	MY46110673	26-Jan-18 (CTTL, No.J18X00894)	Jan-19

	Name	Function	Signature
Calibrated by:	Zhao Jing	SAR Test Engineer	2. the
Reviewed by:	Qi Dianyuan	SAR Project Leader	wor
Approved by:	Lu Bingsong	Deputy Director of the laboratory	- m. usur.
		Issued: Jun 17	
This calibration certifi	cate shall not be reprodu	ced except in full without written approval of	the laboratory.

Certificate No: Z18-97091

Page 1 of 8

Shenzhen Anbotek Compliance Laboratory Limited

Address: 1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 755–26066440 Fax: (86) 755–26014772 Email: service@anbotek.com

FCC ID: 2AV3G-TX12

Page 55 of



Tel: +86-10-62304633-2079 E-mail: cttl@chinattl.com

Add: No.51 Xueyuan Road, Haidian District, Beijing, 100191, China Fax: +86-10-62304633-2504 Http://www.chinattl.cn

e

Glossary:

Anbotek

Product Safety

TSL	tissue simulating liquid
ConvF	sensitivity in TSL / NORMx,y,z
N/A	not applicable or not measured

Calibration is Performed According to the Following Standards:

p

- a) IEEE Std 1528-2013, "IEEE Recommended Practice for Determining the Peak Spatial-Averaged Specific Absorption Rate (SAR) in the Human Head from Wireless Communications Devices: Measurement Techniques", June 2013
- b) IEC 62209-1, "Procedure to measure the Specific Absorption Rate (SAR) For hand-held devices used in close proximity to the ear (frequency range of 300MHz to 3GHz)", February 2005
- c) IEC 62209-2, "Procedure to measure the Specific Absorption Rate (SAR) For wireless communication devices used in close proximity to the human body (frequency range of 30MHz to 6GHz)", March 2010
- d) KDB865664, SAR Measurement Requirements for 100 MHz to 6 GHz

Additional Documentation:

e) DASY4/5 System Handbook

Methods Applied and Interpretation of Parameters:

- Measurement Conditions: Further details are available from the Validation Report at the end of the certificate. All figures stated in the certificate are valid at the frequency indicated.
- Antenna Parameters with TSL: The dipole is mounted with the spacer to position its feed point exactly below the center marking of the flat phantom section, with the arms oriented parallel to the body axis.
- Feed Point Impedance and Return Loss: These parameters are measured with the dipole positioned under the liquid filled phantom. The impedance stated is transformed from the measurement at the SMA connector to the feed point. The Return Loss ensures low reflected power. No uncertainty required.
- Electrical Delay: One-way delay between the SMA connector and the antenna feed point. No uncertainty required.
- SAR measured: SAR measured at the stated antenna input power.
- SAR normalized: SAR as measured, normalized to an input power of 1 W at the antenna connector.
- SAR for nominal TSL parameters: The measured TSL parameters are used to calculate the nominal SAR result.

The reported uncertainty of measurement is stated as the standard uncertainty of Measurement multiplied by the coverage factor k=2, which for a normal distribution Corresponds to a coverage probability of approximately 95%.

She Certificate No: Z18-97091

Page 2 of 8

Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. el:(86) 755-26066440 Fax: (86) 755-26014772 Email: service@anbotek.con

400-003-0500 www.anbotek.com



FCC ID: 2AV3G-TX12





Tel: +86-10-62304633-2079 E-mail: cttl@chinattl.com

Add: No.51 Xueyuan Road, Haidian District, Beijing, 100191, China Fax: +86-10-62304633-2504 Http://www.chinattl.cn

а

Measurement Conditions

DASY system configuration, as far as not given on page 1.

DASY Version	DASY52	52.8.8.1258
Extrapolation	Advanced Extrapolation	
Phantom	Triple Flat Phantom 5.1C	
Distance Dipole Center - TSL	10 mm	with Spacer
Zoom Scan Resolution	dx, dy, dz = 5 mm	
Frequency	2450 MHz ± 1 MHz	

Head TSL parameters

The following parameters and calculations were applied.

Temperature	Permittivity	Conductivity
22.0 °C	39.2	1.80 mho/m
(22.0 ± 0.2) °C	39.0 ± 6 %	1.77 mho/m ± 6 %
<1.0 °C		
	22.0 °C (22.0 ± 0.2) °C	22.0 °C 39.2 (22.0 ± 0.2) °C 39.0 ± 6 %

SAR result with Head TSL

SAR averaged over 1 cm ³ (1 g) of Head TSL	Condition	
SAR measured	250 mW input power	13.0 mW / g
SAR for nominal Head TSL parameters	normalized to 1W	52.4 mW /g ± 20.8 % (k=2)
SAR averaged over 10 cm ³ (10 g) of Head TSL	Condition	
SAR measured	250 mW input power	6.06 mW / g
SAR for nominal Head TSL parameters	normalized to 1W	24.3 mW /g ± 20.4 % (k=2)

Body TSL parameters

The following parameters and calculations were applied.

	Temperature	Permittivity	Conductivity
Nominal Body TSL parameters	22.0 °C	52.7	1.95 mho/m
Measured Body TSL parameters	(22.0 ± 0.2) °C	52.9 ± 6 %	1.97 mho/m ± 6 %
Body TSL temperature change during test	<1.0 °C		

SAR result with Body TSL

SAR averaged over 1 cm^3 (1 g) of Body TSL	Condition	
SAR measured	250 mW input power	13.0 mW / g
SAR for nominal Body TSL parameters	normalized to 1W	51.8 mW /g ± 20.8 % (k=2)
SAR averaged over 10 cm ³ (10 g) of Body TSL	Condition	
SAR measured	250 mW input power	6.18 mW / g
SAR for nominal Body TSL parameters	normalized to 1W	24.7 mW /g ± 20.4 % (k=2)

Shenz

Certificate No: Z18-97091

Page 3 of 8

Addres Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 755-26066440 Fax: (86) 755-26014772 Email: service@anbotek.com

400-003-0500 www.anbotek.com



FCC ID: 2AV3G-TX12

Page 57 of 62



Add: No.51 Xueyuan Road, Haidian District, Beijing, 100191, China Tel: +86-10-62304633-2079 Fax: +86-10-62304633-2504 E-mail: ettl@chinattl.com Http://www.chinattl.cn

Appendix

Antenna Parameters with Head TSL

Impedance, transformed to feed point	54.6Ω+ 2.77jΩ	
Return Loss	- 25.8dB	

Antenna Parameters with Body TSL

Impedance, transformed to feed point	50.7Ω+ 4.28jΩ
Return Loss	- 27.3dB

General Antenna Parameters and Design

Electrical Delay (one direction)	1.263 ns	
----------------------------------	----------	--

After long term use with 100W radiated power, only a slight warming of the dipole near the feedpoint can be measured.

The dipole is made of standard semirigid coaxial cable. The center conductor of the feeding line is directly connected to the second arm of the dipole. The antenna is therefore short-circuited for DC-signals. On some of the dipoles, small end caps are added to the dipole arms in order to improve matching when loaded according to the position as explained in the "Measurement Conditions" paragraph. The SAR data are not affected by this change. The overall dipole length is still according to the Standard. No excessive force must be applied to the dipole arms, because they might bend or the soldered connections near the feedpoint may be damaged.

Additional EUT Data

Manufactured by SPEAG

Certificate No: Z18-97091

Page 4 of 8

Shenzhen Anbotek Compliance Laboratory Limited

Address: 1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 755–26066440 Fax: (86) 755–26014772 Email: service@anbotek.com



FCC ID: 2AV3G-TX12





Add: No.51 Xueyuan Road, Haidian District, Beijing, 100191, China Tel: +86-10-62304633-2079 Fax: +86-10-62304633-2504 E-mail: ettl@chinattl.com Http://www.chinattl.cn

DASY5 Validation Report for Head TSL

Date: 06.15.2018

Test Laboratory: CTTL, Beijing, China DUT: Dipole 2450 MHz; Type: D2450V2; Serial: D2450V2 - SN: 910

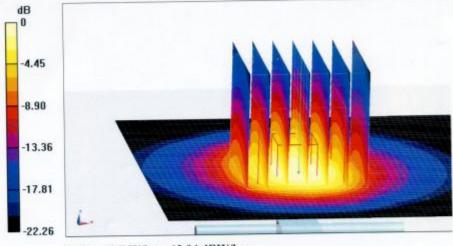
Communication System: UID 0, CW; Frequency: 2450 MHz; Duty Cycle: 1:1 Medium parameters used: f = 2450 MHz; σ = 1.767 S/m; ϵ r = 39.01; ρ = 1000 kg/m3 Phantom section: Right Section Measurement Standard: DASY5 (IEEE/IEC/ANS1 C63.19-2007)

DASY5 Configuration:

- Probe: EX3DV4 SN7307; ConvF(7.36, 7.36, 7.36); Calibrated: 2/19/2018;
- Sensor-Surface: 2mm (Mechanical Surface Detection)
- Electronics: DAE4 Sn771; Calibrated: 2018-02-02
- Phantom: Triple Flat Phantom 5.1C; Type: QD 000 P51 CA; Serial: 1161/1
- Measurement SW: DASY52, Version 52.8 (8); SEMCAD X Version 14.6.10 (7372)

Dipole Calibration/Zoom Scan (7x7x7) (7x7x7)/Cube 0: Measurement grid: dx=5mm, dy=5mm, dz=5mm

Reference Value = 106.5 V/m; Power Drift = 0.02 dB Peak SAR (extrapolated) = 26.7 W/kg SAR(1 g) = 13 W/kg; SAR(10 g) = 6.06 W/kg Maximum value of SAR (measured) = 19.7 W/kg



0 dB = 19.7 W/kg = 12.94 dBW/kg

Certificate No: Z18-97091

Page 5 of 8

Shenzhen Anbotek Compliance Laboratory Limited

Address: 1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 755–26066440 Fax: (86) 755–26014772 Email: service@anbotek.com

Anbotek Product Safety

Report No.: 18220WC00163202

FCC ID: 2AV3G-TX12



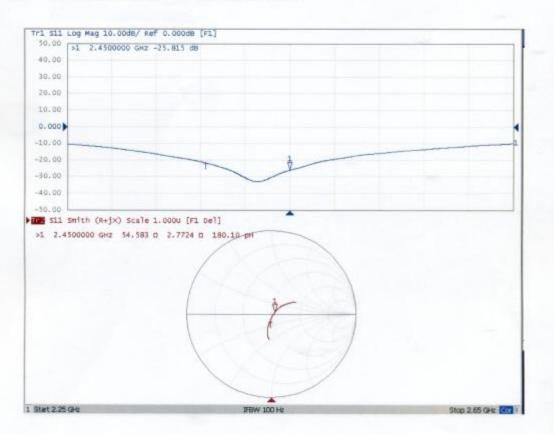


 Add: No.51 Xueyuan Road, Haidian District, Beijing, 100191, China

 Tel: +86-10-62304633-2079
 Fax: +86-10-62304633-2504

 E-mail: cttl@chinattLcom
 Http://www.chinattLcn

Impedance Measurement Plot for Head TSL



Certificate No: Z18-97091

Page 6 of 8

Shenzhen Anbotek Compliance Laboratory Limited

Address: 1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 755–26066440 Fax: (86) 755–26014772 Email: service@anbotek.com



Anbot

Product Safety

FCC ID: 2AV3G-TX12



DASY5 Validation Report for Body TSL

Date: 06.15.2018

Page 60 of 62

Test Laboratory: CTTL, Beijing, China **DUT: Dipole 2450 MHz; Type: D2450V2; Serial: D2450V2 - SN: 910** Communication System: UID 0, CW; Frequency: 2450 MHz; Duty Cycle: 1:1 Medium parameters used: f = 2450 MHz; $\sigma = 1.972$ S/m; $\epsilon_r = 52.92$; $\rho = 1000$ kg/m³ Phantom section: Center Section Measurement Standard: DASY5 (IEEE/IEC/ANSI C63.19-2007)

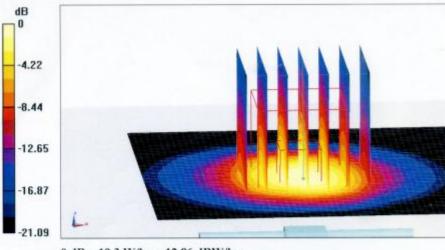
DASY5 Configuration:

- Probe: EX3DV4 SN7307; ConvF(7.22, 7.22, 7.22); Calibrated: 2/19/2018;
- Sensor-Surface: 2mm (Mechanical Surface Detection)
- Electronics: DAE4 Sn771; Calibrated: 2018-02-02
- Phantom: Triple Flat Phantom 5.1C; Type: QD 000 P51 CA; Serial: 1161/1
- Measurement SW: DASY52, Version 52.8 (8); SEMCAD X Version 14.6.10 (7372)

Dipole Calibration/Zoom Scan (7x7x7) (7x7x7)/Cube 0: Measurement grid: dx=5mm, dy=5mm, dz=5mm

Reference Value = 98.89 V/m; Power Drift = 0.03 dB Peak SAR (extrapolated) = 25.6 W/kg

SAR(1 g) = 13 W/kg; SAR(10 g) = 6.18 W/kg Maximum value of SAR (measured) = 19.3 W/kg



0 dB = 19.3 W/kg = 12.86 dBW/kg

Certificate No: Z18-97091

Page 7 of 8

Shenzhen Anbotek Compliance Laboratory Limited

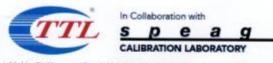
Address: 1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 755–26066440 Fax: (86) 755–26014772 Email: service@anbotek.com

Anbotek Product Safety

Report No.: 18220WC00163202

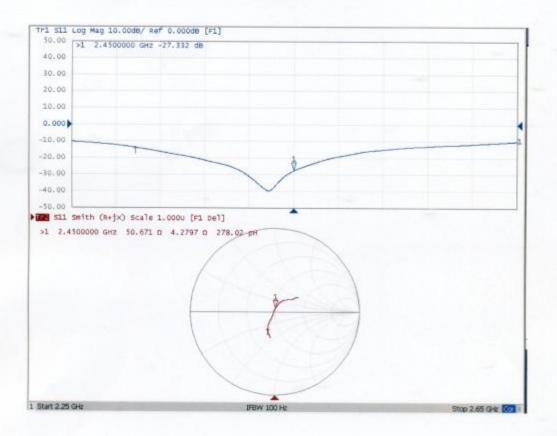
FCC ID: 2AV3G-TX12





Add: No.51 Xueyuan Road, Haidian District, Beijing, 100191, China Tel: +86-10-62304633-2079 Fax: +86-10-62304633-2504 E-mail: ettl@chinattl.com Http://www.chinattl.en

Impedance Measurement Plot for Body TSL



Certificate No: Z18-97091

Page 8 of 8

Shenzhen Anbotek Compliance Laboratory Limited

Address: 1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 755–26066440 Fax: (86) 755–26014772 Email: service@anbotek.com



 Report No.: 18220WC00163202
 FCC ID: 2AV3G-TX12
 Page 62 of 62

*****END OF REPORT*****

Shenzhen Anbotek Compliance Laboratory Limited

Address: 1/F., Building D, Sogood Science and Technology Park, Sanwei Community, Hangcheng Street, Bao'an District, Shenzhen, Guangdong, China. Tel:(86) 755–26066440 Fax: (86) 755–26014772 Email: service@anbotek.com